

IEEE SW Test Workshop

Semiconductor Wafer Test Workshop

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THE EVOLUTION OF A VERSATILE PROBE CARD LOADER-TRANSPORT TROLLEY



Wayne Nelson

General Manager - USA

Email: w.nelson@turbodynamics-usa.com

Bernd Niess

Product Manager - Germany

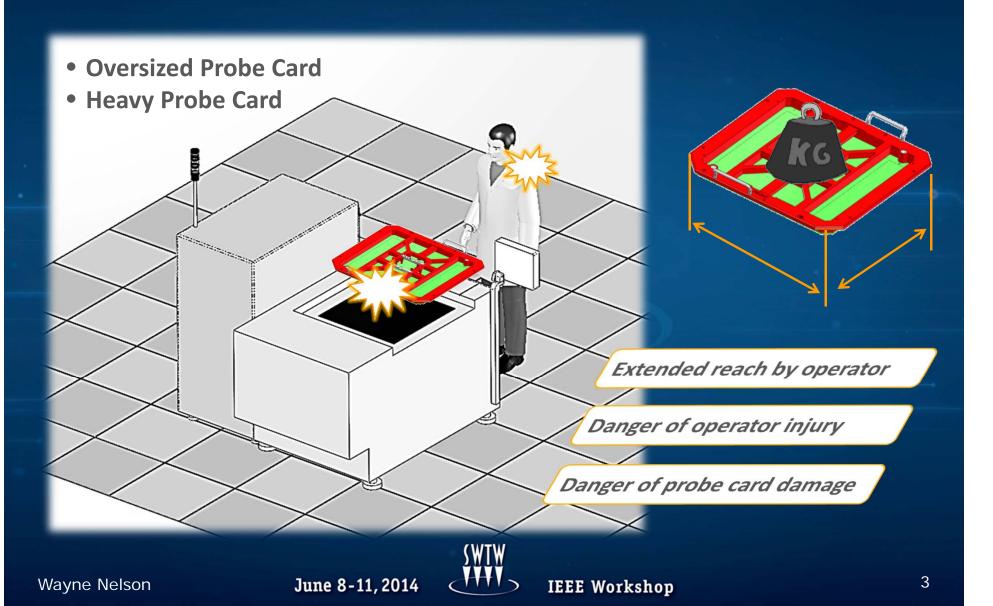
Overview

- Problem Statement
- Prototype Concept
- Specification of Design Requirements
- Mission Statements
- Project Scope Redefined
- The Solution
- The Future
- Summary

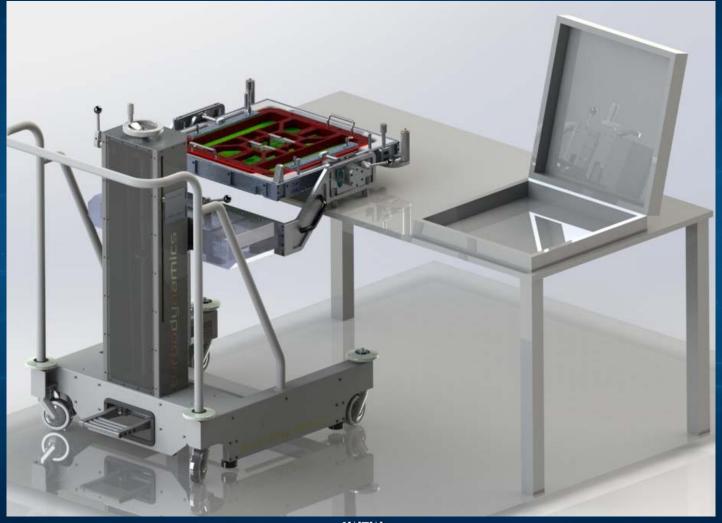
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The Problem



Manual Loading Station

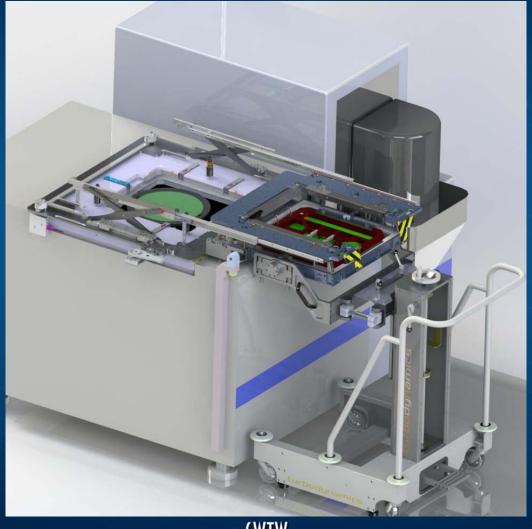


Transport



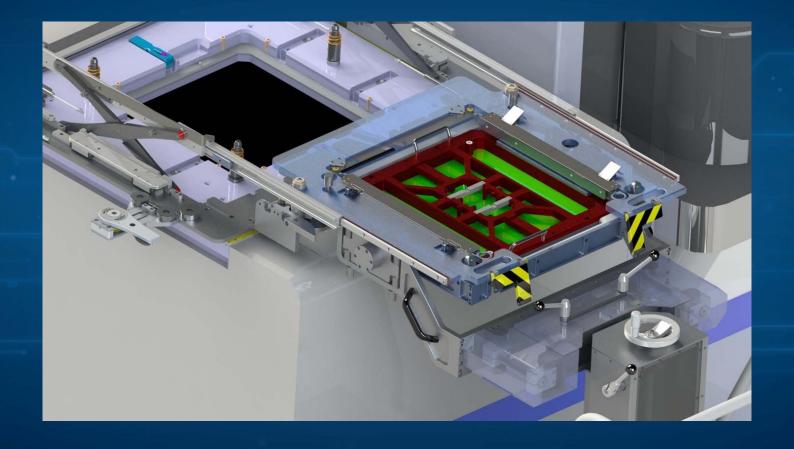


Prober Introduction

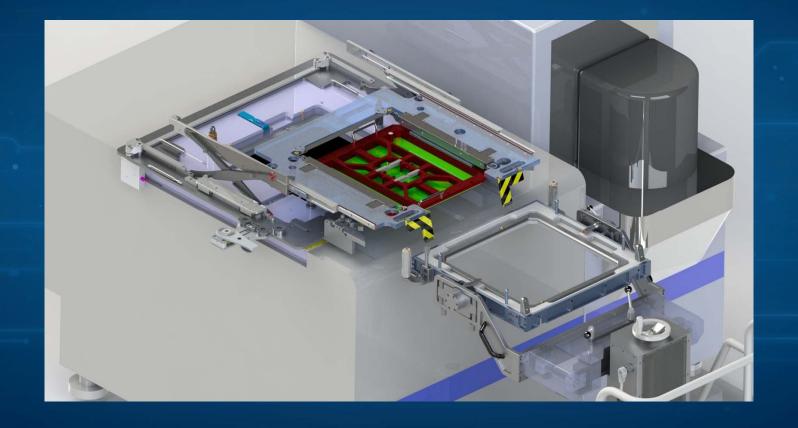




Handshake



Drawer Closure



Reset





Specs

Mechanical Requirements

- Compatible with all applicable TI head stages and defined interfaces 1.
- Compatible with all Accretech 300mm probers (UF300, UF300A, UF3000, UF3000Exe, FP3000) 2.
- 3. Compatible with Tesec 4170, Tesec 4380, and Rasco SO3000 Strip Handlers
- Work with 12", 18" round probe cards and TI SQ/Strip stiffeners 4.
- 5. Be able to maneuver between 42" min. wide aisleways while holding a probe card
- Probe card pick-up and drop-off time < 3 minutes (Does not include travel time between pick up and 6. drop off points)
- Lift/Cart features can not extend underneath prober 7.
- Arm must self-align to probe card for pick-up from carrier (workstation) or head stage 8.
- Must be able to pick up probe card from probe card carrier box on table between 34" 40" from floor 9.
- 10. Must be able to pick-up and drop-off probe card to probers ranging in height of 27" - 51"
- Arm holding probe card needs to self-align to head stage features 11.
- 12. Must be able to lower probe card into head stage opening aligning to ring insert alignment features (auto-align)
- 13. Must be able to twist probe card from DUT down to DUT up (180 deg. to load onto analyzer)
- Must be able to clear prober side docking hardware (REF 51") 14.

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- Must be able to clear test head with DUT down in the max up manipulator position **15.**
- 16. Arm locks to prevent arm (probe card) from moving during transport



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Specs

Cleanroom Protocol

- These materials can not be used: Polyethylene 1.
- 2. No contamination sources directly over opening of head stage

Electrical Requirements

Rechargeable gel battery 1.

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- 2. Gel battery type with 12 hrs. of run time, 3 hrs. charge time
- Charging system auto switching and compatible with all probe site power requirements 3.
- Cart must have capability to run off of direct power plug and be auto voltage switching 4.
- 5. Manual operation (override) if power failure

Ergo / Safety Requirements

- 1. Must meet Semi S2/S8 standards and TI ESH.
- 2. Meets tip spec with arm extended and 50 lb. load
- Arm mechanism must have crush force of < 50 lbs. 3.
- 4. One person operation (Male or Female)
- 5. Lift must be able to maneuver on 5 deg. ramp safely
- If cart is motorized, can not exceed 4 mph 6.
- 7. Wheel locks to prevent lift from moving during pick-up or release of probe card
- 8. Probe card latching mechanism must be user friendly, require no tools, and hold probe card securely
- Must have safety device to prevent probe card from falling if latching mechanism should fail 9.
- If motorized, arm must maintain current position in case of power failure (auto-braking) 10.
- Arm can not be extended while cart is in motion. 11.
- 12. < 27 lbs. initial and < 10 lbs. to sustain push or pull of cart/manipulator



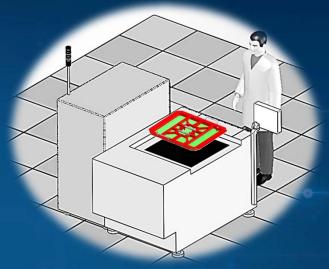
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Mission Challenges

- Secure Transport of the Probe Card to the Prober
 - Safe probe card pickup at the storage
 - Follow test floor guidelines
 - Achieve the technical machine directives (tilting, ...)
 - Exact Probe Card Positioning
 - Vehicle alignment and security to the prober
 - Reference position to the probe card
 - Repeatable positioning
 - Safe Probe Card loading into the Prober's Insert
 - Accessing the prober
 - No interference with the prober head plate or periphery
 - No accidental damage of the needles



Mission Challenges



Fool Proof Operation

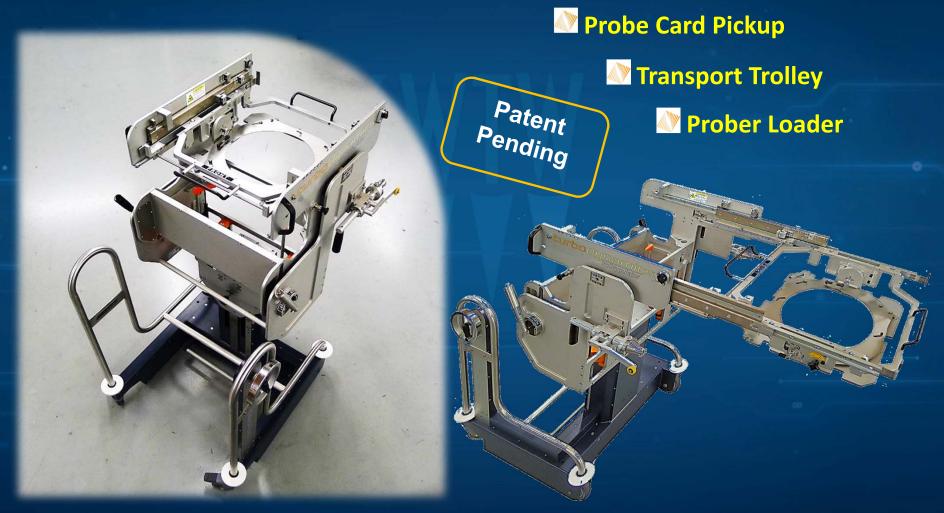
- No accidental release of the probe card
- No accidental collision with environment or prober periphery
- Sequential tasks that require serial execution to avoid operator error

General

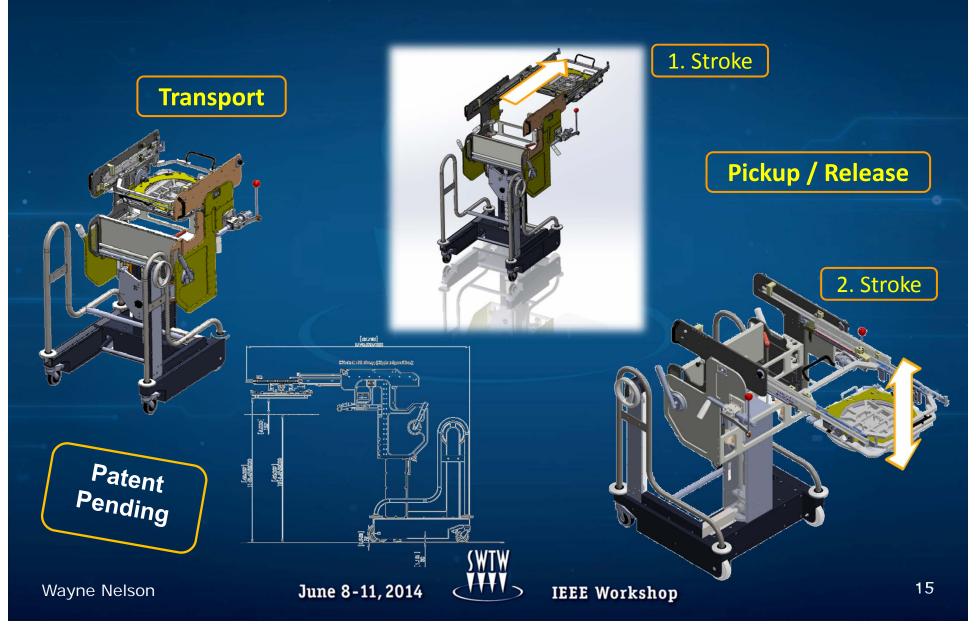
- Easy handling for operators including those of small stature
- Universal for all kinds of probers and probe card types



PC Transport and Feeder in One



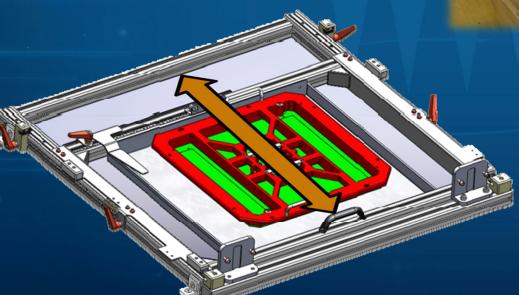
Principle Function



Loading Station

Pickup position can be adjustable for different prober references

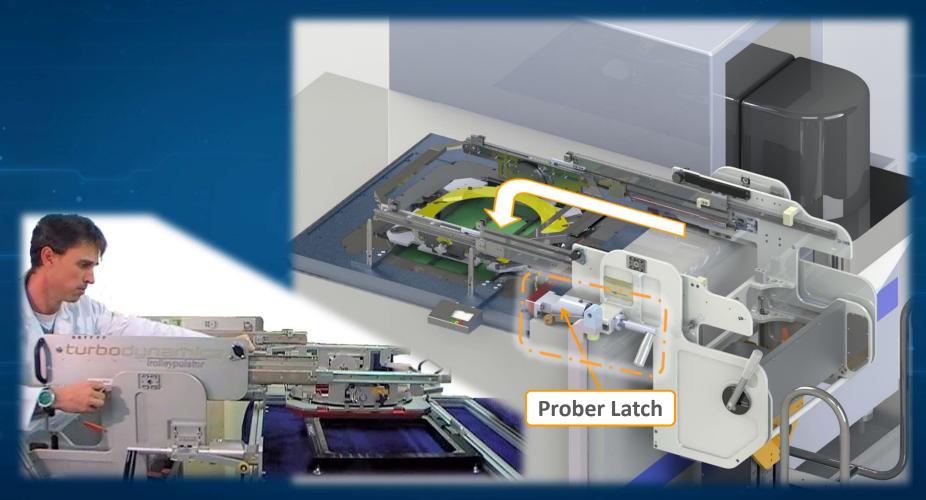




Pickup drawer slides forward for loading and unloading

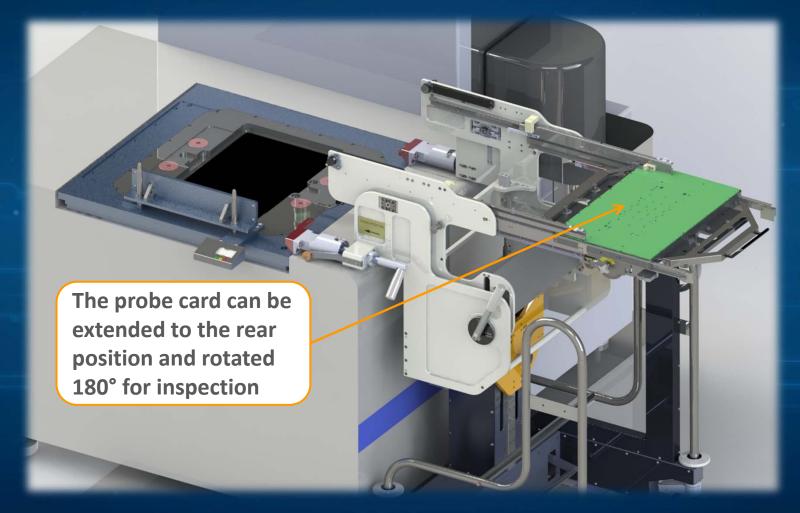


Prober Handshake





Service Position



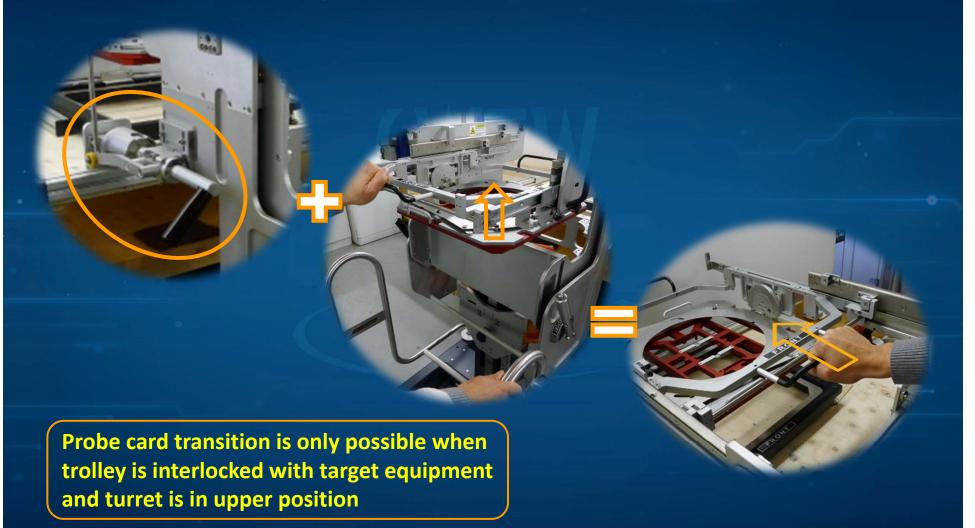
Analyze Probe Card



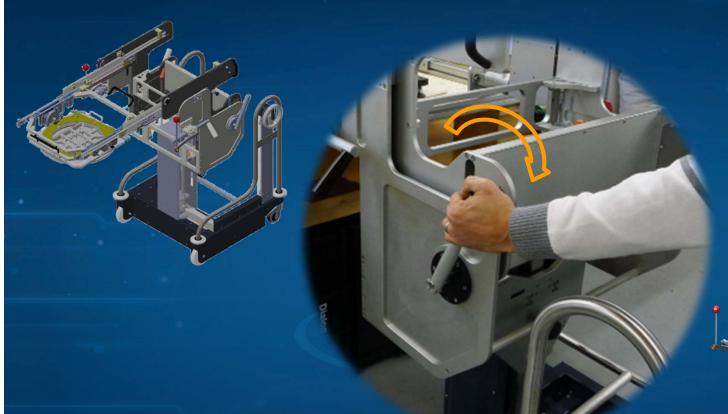
Key Functions



Safety Features



Safety Features



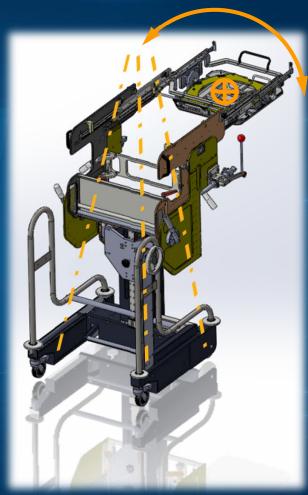
Turret operation (probe card up/down) is only possible when the drawer has reached the extended position



Safety Features



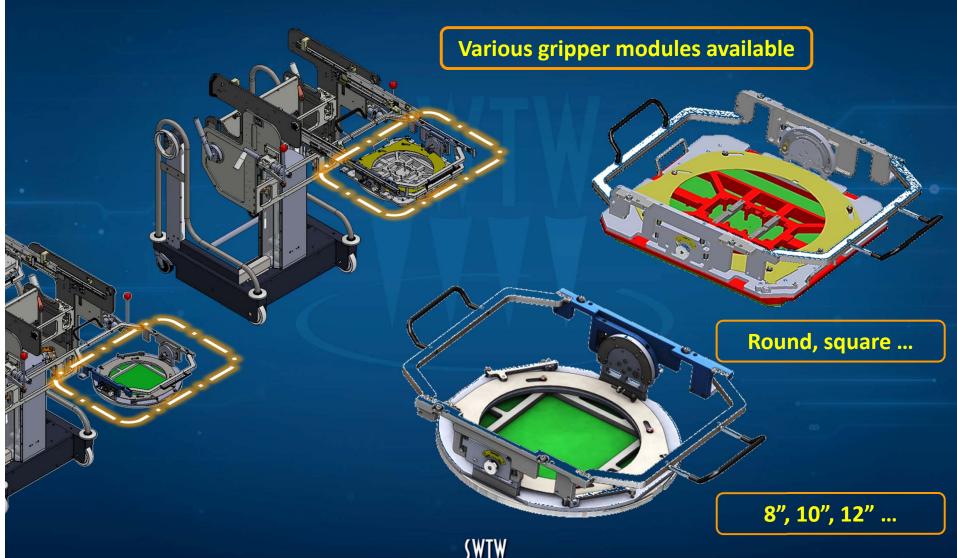
Probe card can only be captured or released after reaching secure destination



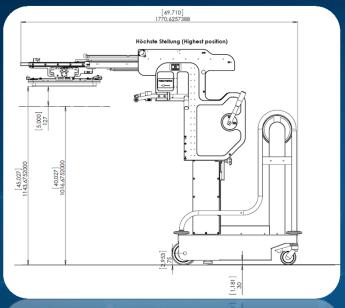
Tilt Prevention

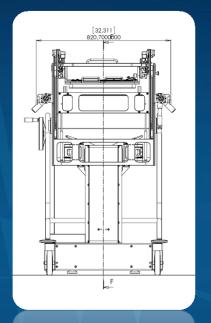


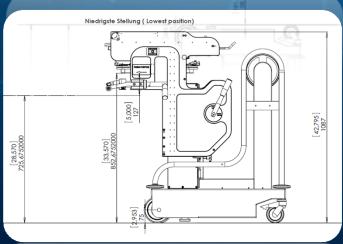
Modular Concept



Specifications Acheived





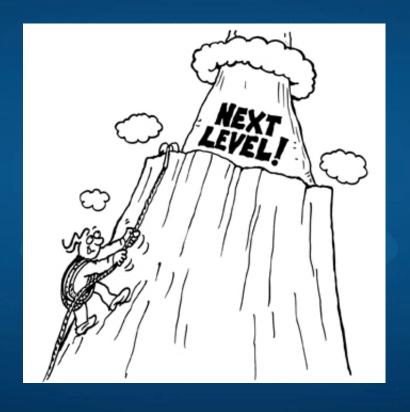




Versatile

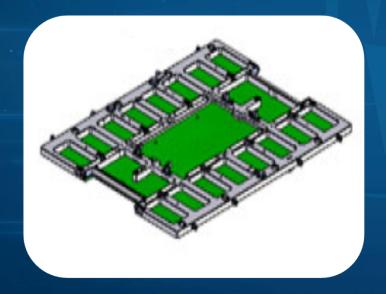


Is "versatile" today... "universal" enough for tomorrow?



Moving Forward

Direct Probe





Moving Forward

Legacy Bottom Loaders





Thank you for your Support!

• Texas Instruments Team:

Lorence Pareja
Dori Robissa
John Campbell
Kelly Daughtry
Kevin Kilpatrick
Kadir Dede
Sharlie Staab